

**Notice of References Cited**

Application/Control No.

10/542,837

Applicant(s)/Patent Under  
Reexamination  
VAN LEEST ET AL.

Examiner

NANCY BITAR

Art Unit

2624

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0250079	12-2004	Kalker et al.	713/176
*	B	US-7,706,569	04-2010	Iwamura, Keiichi	382/100
*	C	US-7,748,051	06-2010	Morimoto et al.	726/32
*	D	US-2006/0129566	06-2006	Van Leest, Adrian Johan	707/100
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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